# NTS0102\_Q100

# Dual supply translating transceiver; open-drain; auto direction sensing

Rev. 1.1 — 12 November 2021

Product data sheet

# 1 General description

The NTS0102-Q100 is a 2-bit, dual supply translating transceiver with auto direction sensing, that enables bidirectional voltage level translation. It features two 2-bit input-output ports (An and Bn), one output enable input (OE) and two supply pins ( $V_{CC(A)}$  and  $V_{CC(B)}$ ).  $V_{CC(A)}$  can be supplied at any voltage between 1.65 V and 3.6 V and  $V_{CC(B)}$  can be supplied at any voltage between 2.3 V and 5.5 V, making the device suitable for translating between any of the voltage nodes (1.8 V, 2.5 V, 3.3 V, and 5.0 V). Pins An and OE are referenced to  $V_{CC(A)}$  and pins Bn are referenced to  $V_{CC(B)}$ . A LOW level at pin OE causes the outputs to assume a high-impedance OFF-state. This device is fully specified for partial power-down applications using  $I_{OFF}$ . The  $I_{OFF}$  circuitry disables the output, preventing the damaging backflow current through the device when it is powered down.

This product has been qualified to the Automotive Electronics Council (AEC) standard Q100 (Grade 1) and is suitable for use in automotive applications.

## 2 Features and benefits

- Automotive product qualification in accordance with AEC-Q100 (Grade 1)
  - Specified from –40 °C to +85 °C and from –40 °C to +125 °C
- · Wide supply voltage range:
  - V<sub>CC(A)</sub>: 1.65 V to 3.6 V and V<sub>CC(B)</sub>: 2.3 V to 5.5 V
- · Maximum data rates:
  - Push-pull: 50 Mbit/s
- I<sub>OFF</sub> circuitry provides partial power-down mode operation
- Inputs accept voltages up to 5.5 V
- ESD protection:
  - MIL-STD-883, method 3015 Class 2 exceeds 2500 V for A port
  - MIL-STD-883, method 3015 Class 3B exceeds 8000 V for B port
  - HBM JESD22-A114E Class 2 exceeds 2500 V for A port
  - HBM JESD22-A114E Class 3B exceeds 8000 V for B port
  - MM JESD22-A115-A exceeds 200 V (C = 200 pF, R = 0  $\Omega$ )
- Latch-up performance exceeds 100 mA per JESD 78B Class II
- · Multiple package options

# 3 Applications

- I<sup>2</sup>C/SMBus
- UART
- GPIO



# **Ordering information**

Table 1. Ordering information

Type number	Topside marking	Package					
		Name	Description	Version			
NTS0102DP-Q100	S02	TSSOP8	plastic thin shrink small outline package; 8 leads; body width 3 mm; lead length 0.5 mm	SOT505-2			
NTS0102GD-Q100	S02	XSON8	plastic extremely thin small outline package; no leads; 8 terminals; body 3 × 2 × 0.5 mm	SOT996-2			
NTS0102TL-Q100	tS2	XSON8	plastic extremely thin small outline package; no leads; 8 terminals; body 3 x 2 x 0.5 mm	SOT1052-2			

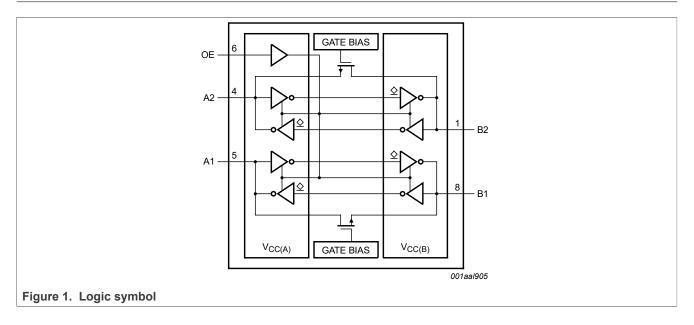
# 4.1 Ordering options

Table 2. Ordering options

Type number	Orderable part number	Package	Packing method <sup>[1]</sup>	Minimum order quantity	Temperature
NTS0102DP-Q100	NTS0102DP-Q100H	TSSOP8	Reel 7" Q3 NDP	3000	–40 °C to +125 °C
NTS0102GD-Q100 <sup>[2]</sup>	NTS0102GD-Q100H	XSON8	Reel 7" Q3 NDP	3000	–40 °C to +125 °C
NTS0102TL-Q100	NTS0102TL-Q100H	XSON8	Reel 7" Q3 NDP	3000	–40 °C to +125 °C

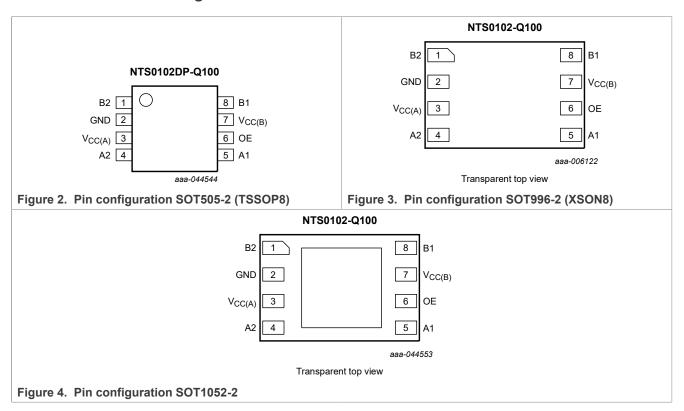
- Standard packing quantities and other packaging data are available at www.nxp.com/packages/Discontinuation Notice 202111012DN drop in replacement is NTS0102TL-Q100H.

# **Functional diagram**



# 6 Pinning information

#### 6.1 Pinning



### 6.2 Pin description

Table 3. Pin description

Table 5. Fill description					
Symbol	Pin	Description			
B2, B1	1, 8	data input or output (referenced to V <sub>CC(B)</sub> )			
GND	2	ground (0 V)			
V <sub>CC(A)</sub>	3	supply voltage A			
A2, A1	4, 5	data input or output (referenced to V <sub>CC(A)</sub> )			
OE	6	output enable input (active HIGH; referenced to V <sub>CC(A)</sub> )			
V <sub>CC(B)</sub>	7	supply voltage B			
n.c.	_	not connected			

# 7 Functional description

Table 4. Function table<sup>[1]</sup>

Supply voltage		Input	Input/output	
V <sub>CC(A)</sub>	V <sub>CC(B)</sub>	OE	An	Bn
1.65 V to V <sub>CC(B)</sub>	2.3 V to 5.5 V	L	Z	Z

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Table 4. Function table [1]...continued

Supply voltage		ipply voltage Input I		
V <sub>CC(A)</sub> V <sub>CC(B)</sub>		OE	An	Bn
1.65 V to V <sub>CC(B)</sub>	2.3 V to 5.5 V	Н	input or output	output or input
GND <sup>[2]</sup>	GND <sup>[2]</sup>	X	Z	Z

 $H = HIGH \ voltage \ level; \ L = LOW \ voltage \ level; \ X = don't \ care; \ Z = high-impedance \ OFF-state.$  When either  $V_{CC(A)}$  or  $V_{CC(B)}$  is at GND level, the device goes into power-down mode.

# **Limiting values**

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CC(A)</sub>	supply voltage A		-0.5	+6.5	V
V <sub>CC(B)</sub>	supply voltage B		-0.5	+6.5	V
VI	input voltage		<sup>] [2]</sup> –0.5	+6.5	V
		B port [1	<sup>] [2]</sup> –0.5	+6.5	V
Vo	output voltage	Active mode [1	] [2]		
		A or B port	-0.5	V <sub>CCO</sub> + 0.5	V
		Power-down or 3-state mode	[1]		
		A port	-0.5	+4.6	V
		B port	-0.5	+6.5	V
I <sub>IK</sub>	input clamping current	V <sub>I</sub> < 0 V	-50	_	mA
I <sub>OK</sub>	output clamping current	V <sub>O</sub> < 0 V	-50	_	mA
Io	output current	V <sub>O</sub> = 0 V to V <sub>CCO</sub>	[2]	± 50	mA
I <sub>CC</sub>	supply current	I <sub>CC(A)</sub> or I <sub>CC(B)</sub>	_	100	mA
I <sub>GND</sub>	ground current		-100	_	mA
T <sub>stg</sub>	storage temperature		-65	+150	°C
P <sub>tot</sub>	total power dissipation	T <sub>amb</sub> = -40 °C to +125 °C	[3]	250	mW

The minimum input and minimum output voltage ratings may be exceeded if the input and output current ratings are observed.

#### **Recommended operating conditions** 9

Table 6. Recommended operating conditions<sup>[1][2]</sup>

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CC(A)</sub>	supply voltage A		1.65	3.6	V
V <sub>CC(B)</sub>	supply voltage B		2.3	5.5	V
T <sub>amb</sub>	ambient temperature		-40	+125	°C
Δt/ΔV	input transition rise and fall rate	A or B port; push-pull driving			

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<sup>[2]</sup> 

 $<sup>\</sup>rm V_{CCO}$  is the supply voltage associated with the output. For TSSOP8 package: above 55 °C the value of  $\rm P_{tot}$  derates linearly with 2.5 mW/K. For XSON8 package: above 118 °C the value of Ptot derates linearly with 7.8 mW/K.

Table 6. Recommended operating conditions [1][2]...continued

Symbol	Parameter	Conditions	Min	Max	Unit
		$V_{CC(A)} = 1.65 \text{ V to } 3.6 \text{ V};$ $V_{CC(B)} = 2.3 \text{ V to } 5.5 \text{ V}$	_	10	ns/V
		OE input			
		$V_{CC(A)} = 1.65 \text{ V to } 3.6 \text{ V};$ $V_{CC(B)} = 2.3 \text{ V to } 5.5 \text{ V}$	_	10	ns/V

<sup>[1]</sup> The A and B sides of an unused I/O pair must be held in the same state, both at V<sub>CCI</sub> or both at GND.

#### 10 Static characteristics

Table 7. Typical static characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V); T<sub>amb</sub> = 25 °C.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
I <sub>I</sub>	input leakage current	OE input; $V_1$ = 0 V to 3.6 V; $V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V	_	_	± 1	μA
l <sub>OZ</sub>	OFF-state output current	A or B port; $V_O = 0 \text{ V or } V_{CCO}$ ; $V_{CC(A)} = 1.65 \text{ V to } 3.6 \text{ V}$ ; $V_{CC(B)} = 2.3 \text{ V to } 5.5 \text{ V}$	_	_	± 1	μA
I <sub>OFF</sub>	power-off leakage current	A port; $V_I$ or $V_O$ = 0 V to 3.6 V; $V_{CC(A)}$ = 0 V; $V_{CC(B)}$ = 0 V to 5.5 V	_	_	± 1	μA
		B port; $V_I$ or $V_O$ = 0 V to 5.5 V; $V_{CC(B)}$ = 0 V; $V_{CC(A)}$ = 0 V to 3.6 V	_	_	± 1 μΑ	μA
Cı	input capacitance	OE input; $V_{CC(A)} = 3.3 \text{ V}$ ; $V_{CC(B)} = 3.3 \text{ V}$	_	1	_	pF
C <sub>I/O</sub>	input/output	A port	_	5	_	pF
	capacitance	B port	_	8.5	_	pF
		A or B port; V <sub>CC(A)</sub> = 3.3 V; V <sub>CC(B)</sub> = 3.3 V	_	11	_	pF

<sup>[1]</sup>  $V_{CCO}$  is the supply voltage associated with the output.

Table 8. Typical supply current

At recommended operating conditions; voltages are referenced to GND (ground = 0 V);  $T_{amb}$  = 25 °C.

V <sub>CC(A)</sub>	V <sub>CC(B)</sub>							
	2.5 V		2.5 V 3.3 V		5.0 V	5.0 V		
	I <sub>CC(A)</sub>	I <sub>CC(B)</sub>	I <sub>CC(A)</sub>	I <sub>CC(B)</sub>	I <sub>CC(A)</sub>	I <sub>CC(B)</sub>		
1.8 V	0.1	0.5	0.1	1.5	0.1	4.6	μΑ	
2.5 V	0.1	0.1	0.1	0.8	0.1	3.8	μΑ	
3.3 V	_	_	0.1	0.1	0.1	2.8	μΑ	

<sup>[2]</sup>  $V_{CC(A)}$  must be less than or equal to  $V_{CC(B)}$ .

Table 9. Static characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	−40 ° C t	o +85 ° C	–40 ° C to +125 ° C		Unit
			Min	Max	Min	Max	
V <sub>IH</sub>	HIGH-level	A port					
	input voltage	$V_{CC(A)} = 1.65 \text{ V to } 1.95 \text{ V};$ $V_{CC(B)} = 2.3 \text{ V to } 5.5 \text{ V}$	V <sub>CCI</sub> – 0.2	_	V <sub>CCI</sub> – 0.2	_	V
		V <sub>CC(A)</sub> = 2.3 V to 3.6 V; V <sub>CC(B)</sub> = 2.3 V to 5.5 V	V <sub>CCI</sub> – 0.4	_	V <sub>CCI</sub> – 0.4	_	V
		B port					
		V <sub>CC(A)</sub> = 1.65 V to 3.6 V; V <sub>CC(B)</sub> = 2.3 V to 5.5 V	V <sub>CCI</sub> – 0.4	_	V <sub>CCI</sub> - 0.4	_	V
		OE input					
		V <sub>CC(A)</sub> = 1.65 V to 3.6 V; V <sub>CC(B)</sub> = 2.3 V to 5.5 V	0.65V <sub>CC(A)</sub>	_	0.65V <sub>CC(A)</sub>	_	V
	LOW-level input voltage	A or B port					
		V <sub>CC(A)</sub> = 1.65 V to 3.6 V; V <sub>CC(B)</sub> = 2.3 V to 5.5 V	_	0.15	_	0.15	V
		OE input					
		V <sub>CC(A)</sub> = 1.65 V to 3.6 V; V <sub>CC(B)</sub> = 2.3 V to 5.5 V	_	0.35V <sub>CC(A)</sub>	_	0.35V <sub>CC(A)</sub>	V
V <sub>OH</sub>	HIGH-level	I <sub>O</sub> = -20 μA					
	output voltage	$V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V	0.67V <sub>CCO</sub>	_	0.67V <sub>CCO</sub>	_	V
V <sub>OL</sub>	LOW-level	A or B port; I <sub>O</sub> = 1 mA	2]				
	output voltage	$V_1 \le 0.15 \text{ V}; V_{CC(A)} = 1.65 \text{ V} \text{ to}$ 3.6 V; $V_{CC(B)} = 2.3 \text{ V} \text{ to } 5.5 \text{ V}$	_	0.4	_	0.4	V
lı	input leakage current	OE input; $V_I = 0 \text{ V to } 3.6 \text{ V}; V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)} = 2.3 \text{ V to}$ 5.5 V	_	± 2	_	± 12	μA
l <sub>oz</sub>	OFF-state output current	A or B port; $V_O = 0 \text{ V or } V_{CCO}$ ; $V_{CC(A)} = 1.65 \text{ V to } 3.6 \text{ V; } V_{CC(B)} = 2.3 \text{ V to } 5.5 \text{ V}$	2]	± 2	_	± 12	μΑ
I <sub>OFF</sub>	power-off leakage	A port; $V_1$ or $V_0 = 0$ V to 3.6 V; $V_{CC(A)} = 0$ V; $V_{CC(B)} = 0$ V to 5.5 V	_	± 2	_	± 12	μΑ
	current	B port; V <sub>I</sub> or V <sub>O</sub> = 0 V to 3.6 V; V <sub>CC(B)</sub> = 0 V; V <sub>CC(A)</sub> = 0 V to 3.6 V	_	± 2	_	± 12	μΑ

Table 9. Static characteristics...continued

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	–40 ° C 1	to +85 ° C	–40 ° C to	+125 ° C	Unit
		_	Min	Max	Min	Max	
I <sub>CC</sub>	supply current	$V_{I} = 0 \text{ V or } V_{CCI}; I_{O} = 0 \text{ A}$ [1]					
		I <sub>CC(A)</sub>					
		V <sub>CC(A)</sub> = 1.65 V to 3.6 V; V <sub>CC(B)</sub> = 2.3 V to 5.5 V	_	2.4	_	15	μΑ
		V <sub>CC(A)</sub> = 3.6 V; V <sub>CC(B)</sub> = 0 V	_	2.2	_	15	μA
		V <sub>CC(A)</sub> = 0 V; V <sub>CC(B)</sub> = 5.5 V	_	-1	_	-8	μA
		I <sub>CC(B)</sub>					
		V <sub>CC(A)</sub> = 1.65 V to 3.6 V; V <sub>CC(B)</sub> = 2.3 V to 5.5 V	_	12	_	30	μΑ
		V <sub>CC(A)</sub> = 3.6 V; V <sub>CC(B)</sub> = 0 V	_	-1	_	-5	μA
		V <sub>CC(A)</sub> = 0 V; V <sub>CC(B)</sub> = 5.5 V	_	1	_	6	μA
		$I_{CC(A)} + I_{CC(B)}$					
		V <sub>CC(A)</sub> = 1.65 V to 3.6 V; V <sub>CC(B)</sub> = 2.3 V to 5.5 V	_	14.4	_	30	μΑ

# **Dynamic characteristics**

Table 10. Dynamic characteristics for temperature range -40  $^{\circ}$ C to +85  $^{\circ}$ C<sup>[1]</sup>

Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 7; for wave forms see Figure 5 and Figure 6.

Symbo	I Parameter	Conditions			Vc	C(B)			Unit
			2.5 V ± 0.2 V		3.3 V ± 0.3 V		5.0 V ± 0.5 V		
			Min	Max	Min	Max	Min	Max	
V <sub>CC(A)</sub> =	= 1.8 V ± 0.15 V								
t <sub>PHL</sub>	HIGH to LOW propagation delay	A to B	_	4.6	_	4.7	_	5.8	ns
t <sub>PLH</sub>	LOW to HIGH propagation delay	A to B	_	6.8	_	6.8	_	7.0	ns
t <sub>PHL</sub>	HIGH to LOW propagation delay	B to A	_	4.4	_	4.5	_	4.7	ns
t <sub>PLH</sub>	LOW to HIGH propagation delay	B to A	_	5.3	_	4.5	_	0.5	ns
t <sub>en</sub>	enable time	OE to A; B	_	200	_	200	_	200	ns
t <sub>dis</sub>	disable time	OE to A; no external load [2]	_	25	_	25	_	25	ns
		OE to B; no external load [2]	_	25	_	25	_	25	ns
		OE to A	_	230	_	230	_	230	ns
		OE to B	_	200	_	200	_	200	ns

 $V_{\text{CCI}}$  is the supply voltage associated with the input.  $V_{\text{CCO}}$  is the supply voltage associated with the output.

Table 10. Dynamic characteristics for temperature range -40 °C to +85 °C<sup>[1]</sup>...continued

Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 7; for wave forms see Figure 5 and Figure 6.

Symbol	Parameter	Conditions	V <sub>CC(B)</sub>						
			2.5 V ± 0.2 V		3.3 V :	± 0.3 V	5.0 V	± 0.5 V	
			Min	Max	Min	Max	Min	Max	
t <sub>TLH</sub>	LOW to HIGH	A port	3.2	9.5	2.3	9.3	1.8	7.6	ns
	output transition time	B port	3.3	10.8	2.7	9.1	2.7	7.6	ns
t <sub>THL</sub>	HIGH to LOW	A port	2.0	5.9	1.9	6.0	1.7	13.3	ns
	output transition time	B port	2.9	7.6	2.8	7.5	2.8	10.0	ns
t <sub>sk(o)</sub>	output skew time	between channels [3]	_	0.7	_	0.7	_	0.7	ns
t <sub>W</sub>	pulse width	data inputs	20	_	20	_	20	_	ns
f <sub>data</sub>	data rate		_	50	_	50	_	50	Mbit/s
V <sub>CC(A)</sub> =	2.5 V ± 0.2 V			'		J.	J.	1	
t <sub>PHL</sub>	HIGH to LOW propagation delay	A to B	_	3.2	_	3.3	_	3.4	ns
t <sub>PLH</sub>	LOW to HIGH propagation delay	A to B	_	3.5	_	4.1	_	4.4	ns
t <sub>PHL</sub>	HIGH to LOW propagation delay	B to A	_	3.0	_	3.6	_	4.3	ns
t <sub>PLH</sub>	LOW to HIGH propagation delay	B to A	_	2.5	_	1.6	_	0.7	ns
t <sub>en</sub>	enable time	OE to A; B	_	200	_	200	_	200	ns
t <sub>dis</sub>	disable time	OE to A; no external load [2]	_	20	_	20	_	20	ns
		OE to B; no external load [2]	_	20	_	20	_	20	ns
		OE to A	_	200	_	200	_	200	ns
		OE to B	_	200	_	200	_	200	ns
t <sub>TLH</sub>	LOW to HIGH	A port	2.8	7.4	2.6	6.6	1.8	6.2	ns
	output transition time	B port	3.2	8.3	2.9	7.9	2.4	6.8	ns
t <sub>THL</sub>	HIGH to LOW	A port	1.9	5.7	1.9	5.5	1.8	5.3	ns
	output transition time	B port	2.2	7.8	2.4	6.7	2.6	6.6	ns
t <sub>sk(o)</sub>	output skew time	between channels [3]	_	0.7	_	0.7	_	0.7	ns
t <sub>W</sub>	pulse width	data inputs	20	_	20	_	20	_	ns
f <sub>data</sub>	data rate		_	50	_	50	_	50	Mbit/s
V <sub>CC(A)</sub> =	3.3 V ± 0.3 V						J.	1	
t <sub>PHL</sub>	HIGH to LOW propagation delay	A to B	_	_	_	2.4	_	3.1	ns
t <sub>PLH</sub>	LOW to HIGH propagation delay	A to B	_	_	_	4.2	_	4.4	ns
t <sub>PHL</sub>	HIGH to LOW propagation delay	B to A	_	_	_	2.5	_	3.3	ns

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Table 10. Dynamic characteristics for temperature range -40 °C to +85 °C<sup>[1]</sup>...continued Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 7; for wave forms see Figure 5 and Figure 6.

Symbol	Parameter	Conditions		$V_{CC(B)}$						
					2.5 V ± 0.2 V		3.3 V ± 0.3 V		± 0.5 V	
			•	Min	Max	Min	Max	Min	Max	
t <sub>PLH</sub>	LOW to HIGH propagation delay	B to A		_	_	_	2.5	_	2.6	ns
t <sub>en</sub>	enable time	OE to A; B		_	_	_	200	_	200	ns
t <sub>dis</sub>	disable time	OE to A; no external load	[2]	_	_	_	15	_	15	ns
		OE to B; no external load	[2]	_	_	_	15	_	15	ns
	OE to A		_	_	_	260	_	260	ns	
		OE to B		_	_	_	200	_	200	ns
t <sub>TLH</sub>	LOW to HIGH	A port		_	_	2.3	5.6	1.9	5.9	ns
	output transition time	B port		_	_	2.5	6.4	2.1	7.4	ns
t <sub>THL</sub>	HIGH to LOW	A port		_	_	2.0	5.4	1.9	5.0	ns
	output transition time	B port		_	_	2.3	7.4	2.4	7.6	ns
t <sub>sk(o)</sub>	output skew time	between channels	[3]	_	_	_	0.7	_	0.7	ns
t <sub>W</sub>	pulse width	data inputs		_	_	20	_	20	_	ns
f <sub>data</sub>	data rate			_	_	_	50	_	50	Mbit/s

<sup>[1]</sup>  $t_{en}$  is the same as  $t_{PZL}$  and  $t_{PZH}$ .  $t_{dis}$  is the same as  $t_{PLZ}$  and  $t_{PHZ}$ .

Table 11. Dynamic characteristics for temperature range -40 °C to +125 °C<sup>[1]</sup>

Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 7; for wave forms see Figure 5 and Figure 6.

Symbol	Parameter	Conditions			Vc	C(B)			Unit
			2.5 V ± 0.2 V		3.3 V ± 0.3 V		5.0 V ± 0.5 V		
			Min	Max	Min	Max	Min	Max	
V <sub>CC(A)</sub> =	1.8 V ± 0.15 V				J.			'	
t <sub>PHL</sub>	HIGH to LOW propagation delay	A to B	_	5.8	_	5.9	_	7.3	ns
t <sub>PLH</sub>	LOW to HIGH propagation delay	A to B	_	8.5	_	8.5	_	8.8	ns
t <sub>PHL</sub>	HIGH to LOW propagation delay	B to A	_	5.5	_	5.7	_	5.9	ns
t <sub>PLH</sub>	LOW to HIGH propagation delay	B to A	_	6.7	_	5.7	_	0.7	ns
t <sub>en</sub>	enable time	OE to A; B	_	200	_	200	_	200	ns

<sup>[2]</sup> Delay between OE going LOW and when the outputs are actually disabled.

<sup>[3]</sup> Skew between any two outputs of the same package switching in the same direction.

Table 11. Dynamic characteristics for temperature range -40 °C to +125 °C<sup>[1]</sup>...continued

Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 7; for wave forms see Figure 5 and Figure 6.

Symbol	Parameter	Conditions				V <sub>C</sub>	C(B)			Unit
			_	2.5 V	± 0.2 V	3.3 V :	± 0.3 V	5.0 V	± 0.5 V	
			-	Min	Max	Min	Max	Min	Max	
t <sub>dis</sub>	disable time	OE to A; no external load	[2]	_	30	_	30	_	30	ns
		OE to B; no external load	[2]	_	30	_	30	_	30	ns
		OE to A		_	250	_	250	_	250	ns
		OE to B			220	_	220	_	220	ns
t <sub>TLH</sub>	LOW to HIGH	A port		3.2	11.9	2.3	11.7	1.8	9.5	ns
	output transition time	B port		3.3	13.5	2.7	11.4	2.7	9.5	ns
t <sub>THL</sub>	HIGH to LOW	A port		2.0	7.4	1.9	7.5	1.7	16.7	ns
	output transition time	B port		2.9	9.5	2.8	9.4	2.8	12.5	ns
t <sub>sk(o)</sub>	output skew time	between channels	[3]	_	0.8	_	0.8	_	0.8	ns
t <sub>W</sub>	pulse width	data inputs		20	_	20	_	20	_	ns
f <sub>data</sub>	data rate			_	50		50		50	Mbit/s
V <sub>CC(A)</sub> =	2.5 V ± 0.2 V				1					
t <sub>PHL</sub>	HIGH to LOW propagation delay	A to B		_	4.0	_	4.2	_	4.3	ns
t <sub>PLH</sub>	LOW to HIGH propagation delay	A to B		_	4.4	_	5.2	_	5.5	ns
t <sub>PHL</sub>	HIGH to LOW propagation delay	B to A		_	3.8	_	4.5	_	5.4	ns
t <sub>PLH</sub>	LOW to HIGH propagation delay	B to A		_	3.2	_	2.0	_	0.9	ns
t <sub>en</sub>	enable time	OE to A; B			200	_	200	_	200	ns
t <sub>dis</sub>	disable time	OE to A; no external load	[2]		25	_	25	_	25	ns
		OE to B; no external load	[2]	_	25	_	25	_	25	ns
		OE to A		_	220	_	220	_	220	ns
		OE to B		_	220	_	220	_	220	ns
t <sub>TLH</sub>	LOW to HIGH	A port		2.8	9.3	2.6	8.3	1.8	7.8	ns
	output transition time	B port		3.2	10.4	2.9	9.7	2.4	8.3	ns
t <sub>THL</sub>	HIGH to LOW	A port		1.9	7.2	1.9	6.9	1.8	6.7	ns
	output transition time	B port		2.2	9.8	2.4	8.4	2.6	8.3	ns
t <sub>sk(o)</sub>	output skew time	between channels	[3]	_	0.8	_	0.8	_	0.8	ns
t <sub>W</sub>	pulse width	data inputs		20	_	20	_	20	_	ns
f <sub>data</sub>	data rate			_	50	_	50	_	50	Mbit/s

Table 11. Dynamic characteristics for temperature range -40 °C to +125 °C<sup>[1]</sup>...continued Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 7; for wave forms see Figure 5 and Figure 6.

Symbol	Parameter	Conditions		$V_{CC(B)}$						
				2.5 V ± 0.2 V		3.3 V :	± 0.3 V	5.0 V	± 0.5 V	
			-	Min	Max	Min	Max	Min	Max	
V <sub>CC(A)</sub> =	3.3 V ± 0.3 V				ı	J.		ı		
t <sub>PHL</sub>	HIGH to LOW propagation delay	A to B		_	_	_	3.0	_	3.9	ns
t <sub>PLH</sub>	LOW to HIGH propagation delay	A to B		_	_	_	5.3	_	5.5	ns
t <sub>PHL</sub>	HIGH to LOW propagation delay	B to A		_	_	_	3.2	_	4.2	ns
t <sub>PLH</sub>	LOW to HIGH propagation delay	B to A		_	_	_	3.2	_	3.3	ns
t <sub>en</sub>	enable time	OE to A; B		_	_	_	200	_	200	ns
t <sub>dis</sub>	disable time	OE to A; no external load	[2]	_	_	_	20	_	20	ns
		OE to B; no external load	[2]	_	_	_	20	_	20	ns
		OE to A		_	_	_	280	_	280	ns
		OE to B		_	_	_	220	_	220	ns
t <sub>TLH</sub>	LOW to HIGH	A port		_	_	2.3	7.0	1.9	7.4	ns
	output transition time	B port		_	_	2.5	8.0	2.1	9.3	ns
t <sub>THL</sub>	HIGH to LOW	A port		_	_	2.0	6.8	1.9	6.3	ns
	output transition time	B port		_	_	2.3	9.3	2.4	9.5	ns
t <sub>sk(o)</sub>	output skew time	between channels	[3]	_	_	_	0.8	_	0.8	ns
t <sub>W</sub>	pulse width	data inputs		_	_	20	_	20	_	ns
f <sub>data</sub>	data rate			_	_	_	50	_	50	Mbit/

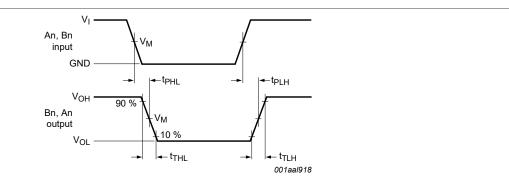
 $t_{\text{en}}$  is the same as  $t_{\text{PZL}}$  and  $t_{\text{PZH}}$ .

t<sub>dis</sub> is the same as t<sub>PLZ</sub> and t<sub>PHZ</sub>.

Delay between OE going LOW and when the outputs are actually disabled.

Skew between any two outputs of the same package switching in the same direction.

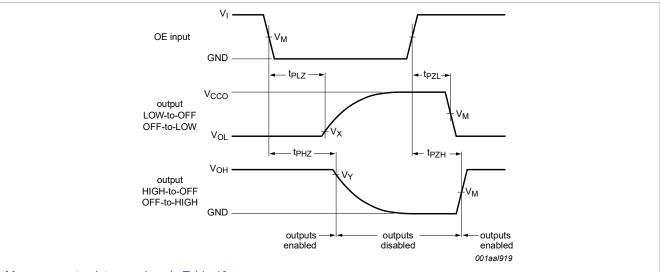
## 12 Waveforms



Measurement points are given in Table 12.

 $V_{\text{OL}}$  and  $V_{\text{OH}}$  are typical output voltage levels that occur with the output load.

Figure 5. The data input (An, Bn) to data output (Bn, An) propagation delay times



Measurement points are given in Table 12.

 $V_{\text{OL}}$  and  $V_{\text{OH}}$  are typical output voltage levels that occur with the output load.

Figure 6. Enable and disable times

Table 12. Measurement points<sup>[1][2]</sup>

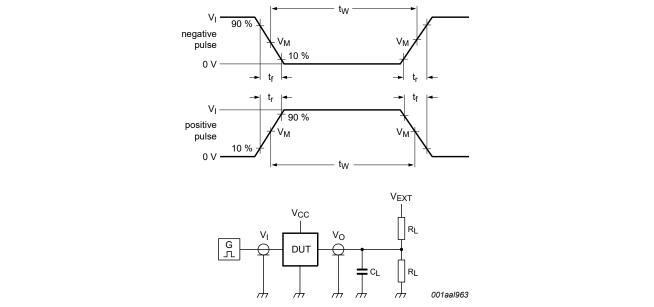
Supply voltage	Input	Output		
V <sub>CCO</sub>	V <sub>M</sub>	V <sub>M</sub>	V <sub>X</sub>	V <sub>Y</sub>
1.8 V ± 0.15 V	0.5V <sub>CCI</sub>	0.5V <sub>CCO</sub>	V <sub>OL</sub> + 0.15 V	V <sub>OH</sub> – 0.15 V
2.5 V ± 0.2 V	0.5V <sub>CCI</sub>	0.5V <sub>CCO</sub>	V <sub>OL</sub> + 0.15 V	V <sub>OH</sub> – 0.15 V
3.3 V ± 0.3 V	0.5V <sub>CCI</sub>	0.5V <sub>CCO</sub>	V <sub>OL</sub> + 0.3 V	V <sub>OH</sub> – 0.3 V
5.0 V ± 0.5 V	0.5V <sub>CCI</sub>	0.5V <sub>CCO</sub>	V <sub>OL</sub> + 0.3 V	V <sub>OH</sub> –0.3 V

<sup>[1]</sup>  $V_{CCI}$  is the supply voltage associated with the input.

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<sup>[2]</sup> V<sub>CCO</sub> is the supply voltage associated with the output.



Test data is given in Table 13.

All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz;  $Z_O = 50 \Omega$ ;  $dV/dt \geq 1.0 V/ns$ .

R<sub>I</sub> = Load resistance.

C<sub>L</sub> = Load capacitance including jig and probe capacitance.

V<sub>EXT</sub> = External voltage for measuring switching times.

Figure 7. Test circuit for measuring switching times

Table 13. Test data

Supply voltage		Input		Load		$V_{EXT}$		
V <sub>CC(A)</sub>	V <sub>CC(B)</sub>	V <sub>I</sub> <sup>[1]</sup>	Δt/ΔV	CL	R <sub>L</sub> <sup>[2]</sup>	t <sub>PLH</sub> , t <sub>PHL</sub>	t <sub>PZH</sub> , t <sub>PHZ</sub>	$t_{PZL}, t_{PLZ}^{[3]}$
1.65 V to 3.6 V	2.3 V to 5.5 V	$V_{CCI}$	≤ 1.0 ns/V	15 pF	50 kΩ, 1 MΩ	open	open	2V <sub>CCO</sub>

<sup>[1]</sup>  $V_{CCI}$  is the supply voltage associated with the input.

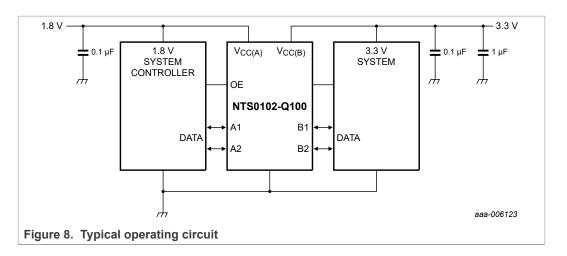
# 13 Application information

#### 13.1 Applications

Voltage level-translation applications. The NTS0102-Q100 can be used in point-to-point applications to interface between devices or systems operating at different supply voltages. The device is primarily targeted at I<sup>2</sup>C or 1-wire which use open-drain drivers. It may also be used in applications where push-pull drivers are connected to the ports although the NTB0102-Q100 may be more suitable.

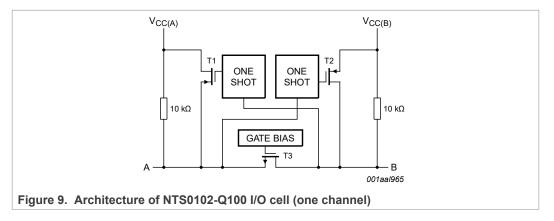
<sup>[2]</sup> For measuring data rate, pulse width, propagation delay, and output rise and fall measurements, R<sub>L</sub> = 1 MΩ; for measuring enable and disable times, R<sub>L</sub> = 50 KΩ.

<sup>[3]</sup>  $V_{\text{CCO}}$  is the supply voltage associated with the output.



#### 13.2 Architecture

The architecture of the NTS0102-Q100 is shown in Figure 9. The device does not require an extra input signal to control the direction of data flow from A to B or B to A.



The NTS0102-Q100 is a "switch" type voltage translator, it employs two key circuits to enable voltage translation:

- 1. A pass-gate transistor (N-channel) that ties the ports together.
- An output edge-rate accelerator that detects and accelerates rising edges on the I/O pins.

The gate bias voltage of the pass gate transistor (T3) is set at approximately one threshold voltage above the  $V_{CC}$  level of the low-voltage side. During a LOW-to-HIGH transition, the output one-shot accelerates the output transition by switching on the PMOS transistors (T1, T2). This action bypasses the 10 k $\Omega$  pullup resistors and increases current drive capability. The one-shot is activated once the input transition reaches approximately  $V_{CCI}/2$ . It is de-activated approximately 50 ns after the output reaches  $V_{CCO}/2$ . During the acceleration time, the driver output resistance is between approximately 50  $\Omega$  and 70  $\Omega$ . To avoid signal contention and minimize dynamic  $I_{CC}$ , before applying a signal in the opposite direction, wait for the one-shot circuit to turn-off. Pullup resistors are included in the device for DC current sourcing capability.

## 13.3 Input driver requirements

As the NTS0102-Q100 is a switch type translator, properties of the input driver directly affect the output signal. The external open-drain or push-pull driver applied to an I/O, determines the static current sinking capability of the system. The max data rate, HIGH-to-LOW output transition time ( $t_{THL}$ ), and propagation delay ( $t_{PHL}$ ) are dependent upon the output impedance and edge-rate of the external driver. The limits provided for these parameters in the data sheet assume a driver with output impedance below 50  $\Omega$  is used.

#### 13.4 Output load considerations

The maximum lumped capacitive load that can be driven is dependent upon the one-shot pulse duration. In cases with very heavy capacitive loading, there is a risk that the output does not reach the positive rail within the one-shot pulse duration.

To avoid excessive capacitive loading, and to ensure correct triggering of the one-shot, use short trace lengths and low capacitance connectors on NTS0102-Q100 PCB layouts. To ensure low impedance termination and avoid output signal oscillations and one-shot re triggering, limit the length of the PCB trace. The PCB trace should be such that the round-trip delay of any reflection is within the one-shot pulse duration (approximately 50 ms).

#### 13.5 Power-up

During operation  $V_{CC(A)}$  must never be higher than  $V_{CC(B)}$ , however during power-up  $V_{CC(A)} \ge V_{CC(B)}$  does not damage the device, so either power supply can be ramped up first. There is no special power-up sequencing required. The NTS0102-Q100 includes circuitry that disables all output ports when either  $V_{CC(A)}$  or  $V_{CC(B)}$  is switched off.

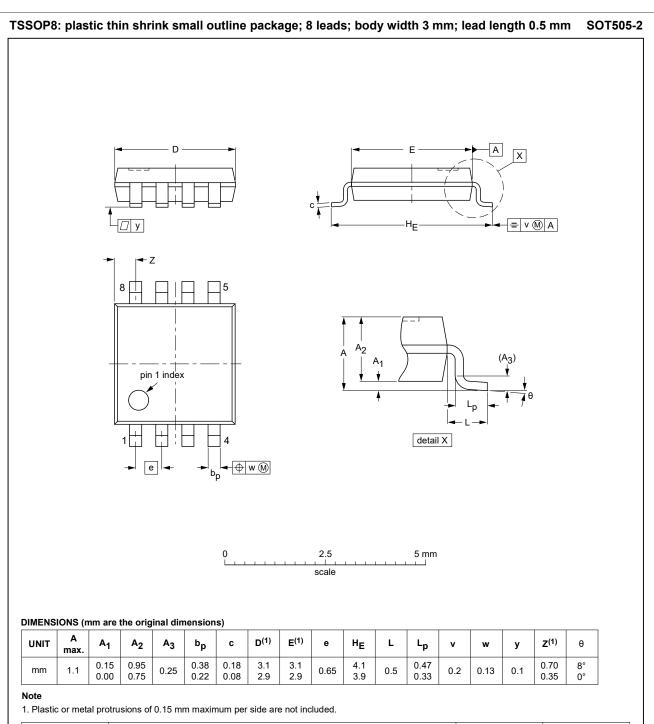
#### 13.6 Enable and disable

An output enable input (OE) is used to disable the device. Setting OE = LOW causes all I/Os to assume the high-impedance OFF-state. The disable time ( $t_{\rm dis}$  with no external load) indicates the delay between when OE goes LOW and when outputs actually become disabled. The enable time ( $t_{\rm en}$ ) indicates the amount of time to allow for one one-shot circuit to become operational after OE is taken HIGH. To ensure the high-impedance OFF-state during power-up or power-down, pin OE should be tied to GND through a pull-down resistor. The current-sourcing capability of the driver determines the minimum value of the resistor.

#### 13.7 Pull-up or pull-down resistors on I/Os lines

Each A port I/O has an internal 10 k $\Omega$  pullup resistor to  $V_{CC(A)}$ . Each B port I/O has an internal 10 k $\Omega$  pullup resistor to  $V_{CC(B)}$ . If a smaller value of pullup resistor is required, an external resistor must be added parallel to the internal 10 k $\Omega$ . The reduction in the value of the pullup resistor affects the  $V_{OL}$  level. When OE goes LOW, the internal pull-ups of the NTS0102-Q100 are disabled.

# 14 Package outline

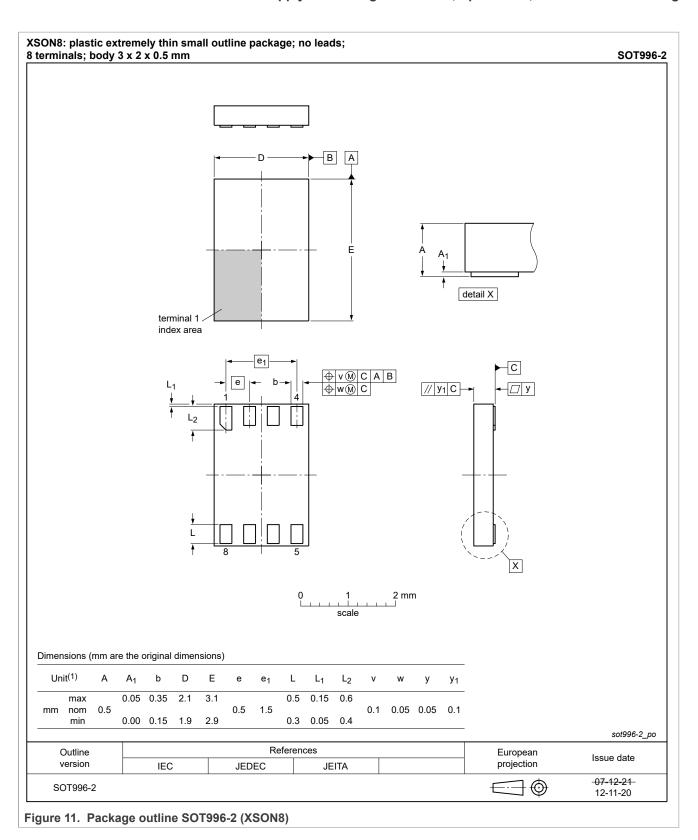


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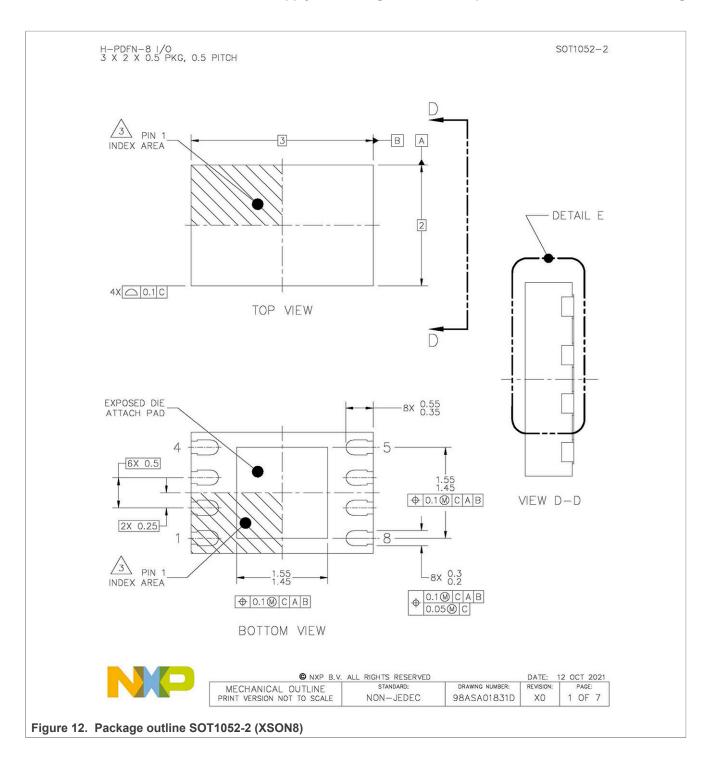
Figure 10. Package outline SOT505-2 (TSSOP8)

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## 15 Abbreviations

#### Table 14. Abbreviations

Acronym	Description
CMOS	Complementary Metal Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
GPIO	General Purpose Input Output
НВМ	Human Body Model
I <sup>2</sup> C	Inter-Integrated Circuit
MIL	Military
MM	Machine Model
РСВ	Printed-Circuit board
PMOS	Positive Metal Oxide Semiconductor
SMBus	System Management Bus
UART	Universal Asynchronous Receiver Transmitter
UTLP	Ultra Thin Leadless Package

# 16 Revision history

Table 15. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
NTS0102_Q100 v.1.1	20211112	Product data sheet	_	NTS0102_Q100 v.1
Modifications:	<ul> <li>NTS0102TL-C</li> <li>Removed the</li> <li>Topside markitable.</li> <li>Section 4.1, add</li> <li>Section 6.1, Figure</li> </ul>	1, revised as follows: 2100: added new row. Temperature range column, ir ng: inserted new column after ed new section including Tablure 4, inserted new figure for Stre 12, added new package output to the section including Tablure 4.	removing the "Marking e 2. 60T1052-2.	
NTS0102_Q100 v.1	20130227	Product data sheet	_	_

## 17 Legal information

#### 17.1 Data sheet status

Document status <sup>[1][2]</sup>	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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